


<b>Search Notes</b> 	<b>Application/Control No.</b> 10660767	<b>Applicant(s)/Patent Under Reexamination</b> NISHIO ET AL.
	<b>Examiner</b> Thanh-Tam T Le	<b>Art Unit</b> 2839

SEARCHED			
Class	Subclass	Date	Examiner
439	140, 141, 152, 157, 159, 160, 630	03/18/10	TL

SEARCH NOTES		
Search Notes	Date	Examiner

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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